

---

# Contents

---

<b>Preface</b> . . . . .	vii
<b>Chapter 1. State-of-the-Art of Infrared Technology</b> . . . . .	1
1.1. Introduction . . . . .	1
1.2. Compound materials III-V . . . . .	2
1.2.1. Historical introduction . . . . .	2
1.2.2. Physical properties of the III-V compounds emission. . . . .	4
1.2.3. Ternary and quaternary compounds . . . . .	18
1.3. Light-emitting diodes . . . . .	21
1.3.1. Introduction . . . . .	21
1.3.2. Epitaxial structures . . . . .	22
1.3.3. LED assembly. . . . .	32
1.4. Applications . . . . .	38
1.4.1. Infrared remote control systems . . . . .	38
1.4.2. Autofocus . . . . .	40
1.4.3. Space. . . . .	42
1.5. Conclusion . . . . .	44
<b>Chapter 2. Analysis and Models of an LED</b> . . . . .	45
2.1. Introduction . . . . .	45
2.2. Physicochemical analysis . . . . .	46
2.2.1. Context and objectives . . . . .	46
2.2.2. Analysis adapted to casing . . . . .	46
2.2.3. Analysis adapted to the chip . . . . .	52
2.3. Electro-optical analysis . . . . .	56
2.3.1. Current–voltage characteristics . . . . .	57
2.3.2. Spectral characteristics . . . . .	60

2.4. Initial characterizations of 935 nm LEDs . . . . .	68
2.4.1. Technological evaluation. . . . .	68
2.4.2. Electro-optical characterization and electrical modeling of the LED . . . . .	70
2.5. Conclusion . . . . .	78
<b>Chapter 3. Physics of Failure Principles . . . . .</b>	<b>79</b>
3.1. Introduction . . . . .	79
3.2. Aging tests . . . . .	80
3.2.1. Sequence of aging campaign. . . . .	80
3.3. Failure signatures . . . . .	86
3.3.1. Functional parameters . . . . .	86
3.3.2. Electrical failure signatures . . . . .	88
3.3.3. Optical failure signatures. . . . .	93
3.4. Physics of failures . . . . .	95
3.4.1. Mechanisms related to transport phenomena . . . . .	95
3.4.2. Electron transition mechanisms . . . . .	110
3.4.3. Model of a defect in a crystal . . . . .	113
3.4.4. Impact of defects on emission properties . . . . .	114
3.5. Conclusion . . . . .	115
<b>Chapter 4. Methodologies of Reliability Analysis. . . . .</b>	<b>117</b>
4.1. Introduction . . . . .	117
4.2. Method based on the physics of failures. . . . .	118
4.2.1. Acceleration and aggravation factor. . . . .	118
4.2.2. Estimation of lifetime distribution. . . . .	121
4.2.3. Line input sorting of a component. . . . .	124
4.3. Digital methods . . . . .	127
4.3.1. General points. . . . .	127
4.3.2. Application: cases of emissive optoelectronic systems. . . . .	128
4.3.3. Conclusions . . . . .	130
4.4. A new approach . . . . .	131
4.4.1. Context and method . . . . .	131
4.4.2. LEDs studied . . . . .	131
4.4.3. Gamma irradiation . . . . .	149
4.4.4. Neutron irradiation . . . . .	153
4.5. Conclusion . . . . .	159
<b>Bibliography. . . . .</b>	<b>161</b>
<b>Index . . . . .</b>	<b>163</b>